

# MURD2020CT

Rev.F May.-2016

## / Descriptions

TO-252

Ultrafast Recovery Diode in a TO-252 Plastic Package.

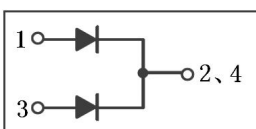
## / Features

Silicon epitaxial process to produce ultrafast recovery diode with low reverse leakage current and high reliability.

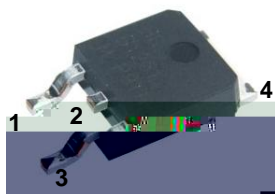
## / Applications

For high frequency, high voltage, high current rectifier diode, freewheeling diode.

## / Equivalent Circuit



## / Pinning



PIN1 Anode

PIN 2 4 Cathode

PIN 3 Anode

## / $h_{FE}$ Classifications & Marking

See Marking Instructions.

**/ Absolute Maximum Ratings(Ta=25 )**

Parameter	Symbol	Rating	Unit
Peak Repetitive Reverse Voltage	$V_{RRM}$	200	V
RMS Reverse Voltage	$V_{RMS}$	140	V
DC Blocking Voltage	$V_{DC}$	200	V
Average Forward Current	$I_F$	2 10	A
Non Repetitive Peak Surge Current	$I_{FSM}$	120	A
Thermal Resistance Junction to Case	$R_{Jc}$	2.8	/W
Operating and Storage Temperature Range	$T_j$ $T_{stg}$	-55 150	

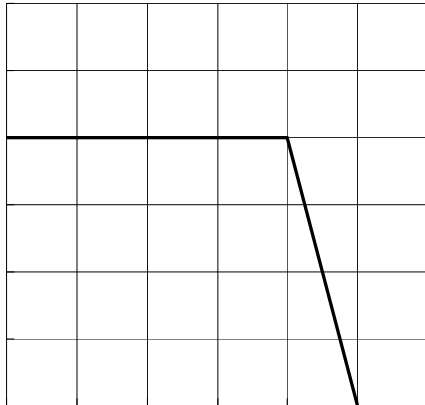
**/ Electrical Characteristics(Ta=25 )**

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Forward Voltage	$V_F$	$I_F=2A$ $T_c=25$		0.79		V
		$I_F=2A$ $T_c=125$		0.65		V
		$I_F=10A$ $T_c=25$		0.95	1.0	V
		$I_F=10A$ $T_c=125$		0.84	0.9	V
Instantaneous Reverse Current	$I_R$ Note 1	$V_R=200V$ $T_a=25$			10	A
		$V_R=200V$ $T_a=125$			150	A
Reverse Recovery Time	$t_{rr}$	$I_F=0.5A$ $I_R=1.0A$ $I_{RR}=0.25A$			35	ns

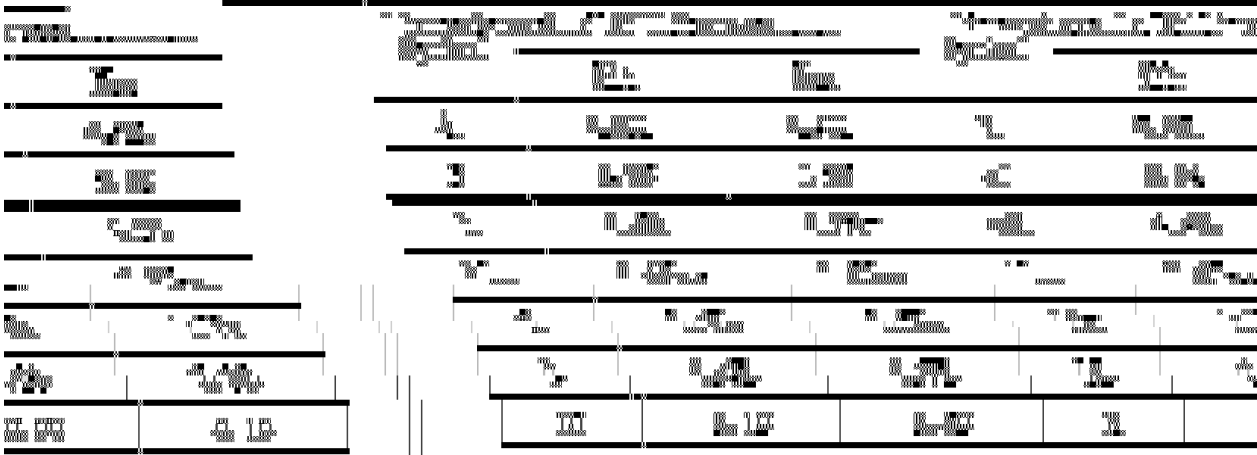
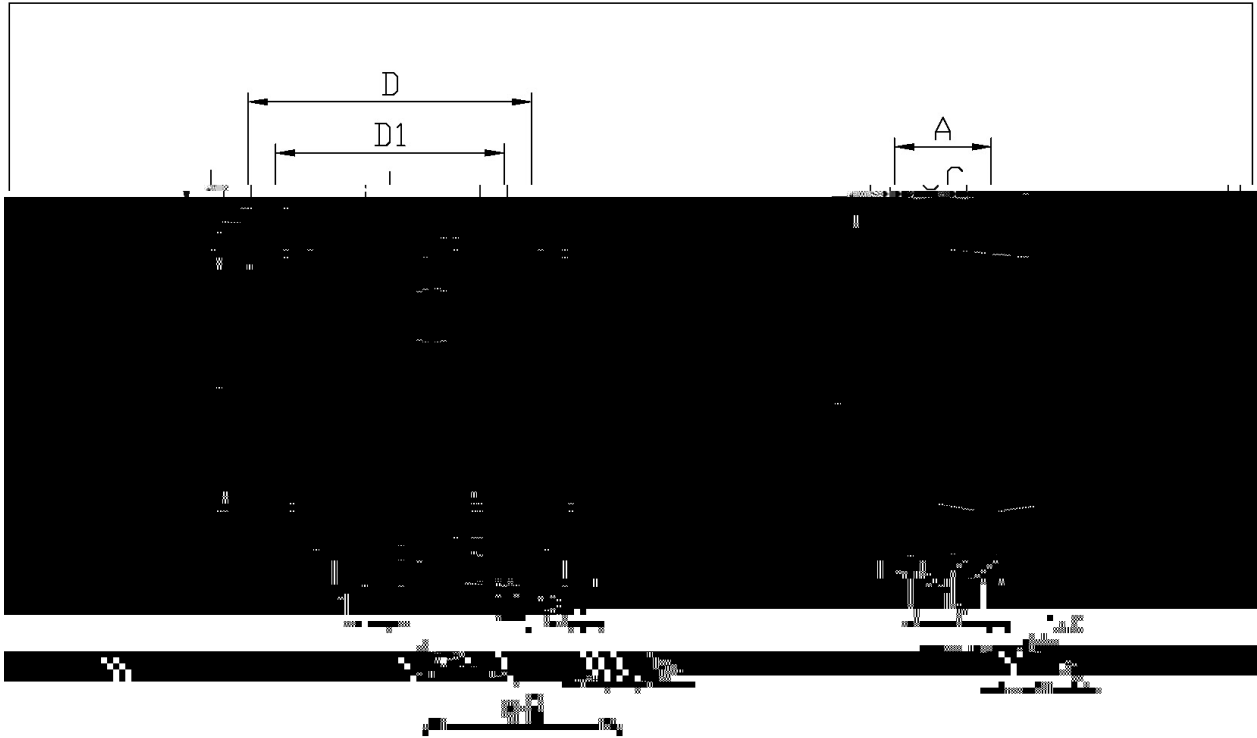
/Notes

1. /Short duration pulse test used to minimize self-heating effect.
2. / Unless otherwise noted, values for the parameters of a single chip

/ **Electrical Characteristic Curve**



/ Package Dimensions



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## / Marking Instructions



BR

MURD2020

CT:

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Note:

BR: Company Code

MURD2020 Product Type.

CT: Internal Structure

\*\*\*\*: Lot No. Code, code change with Lot No.

